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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, SPI, UART/USART
Peripherals	DMA, I²S, LCD, LVD, POR, PWM, WDT
Number of I/O	54
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 20x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkl33z256vlh4

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Table 7. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit	Notes
	• 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OL} = 18 mA • 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OL} = 6 mA	—	0.5	V	
I_{OLT}	Output low current total for all ports	—	100	mA	
I_{IN}	Input leakage current (per pin) for full temperature range	—	1	µA	2
I_{IN}	Input leakage current (per pin) at 25 °C	—	0.025	µA	2
I_{IN}	Input leakage current (total all pins) for full temperature range	—	64	µA	2
I_{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	µA	
R_{PU}	Internal pullup resistors	20	50	kΩ	3

1. PTB0, PTB1, PTC3, PTC4, PTD6, and PTD7 I/O have both high drive and normal drive capability selected by the associated PTx_PCRn[DSE] control bit. All other GPIOs are normal drive only.
2. Measured at V_{DD} = 3.6 V
3. Measured at V_{DD} supply voltage = V_{DD} min and Vinput = V_{SS}

2.2.4 Power mode transition operating behaviors

All specifications except t_{POR} and VLLSx→RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 48 MHz
- Bus and flash clock = 24 MHz
- HIRC clock mode

Table 8. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.8 V to execution of the first instruction across the operating temperature range of the chip.	—	—	300	µs	1
	• VLLS0 → RUN	—	152	166	µs	
	• VLLS1 → RUN	—	152	166	µs	
	• VLLS3 → RUN	—	93	104	µs	
	• LLS → RUN	—	7.5	8	µs	

Table continues on the next page...

Table 8. Power mode transition operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• VLPS → RUN	—	7.5	8	µs	
	• STOP → RUN	—	7.5	8	µs	

1. Normal boot (FTFA_FOPT[LPBOOT]=11)

2.2.5 Power consumption operating behaviors

The maximum values stated in the following table represent characterized results equivalent to the mean plus three times the standard deviation (mean + 3 sigma).

NOTE

The while (1) test is executed with flash cache enabled.

Table 9. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DDA}	Analog supply current	—	—	See note	mA	1
I_{DD_RUNCO}	Running CoreMark in flash in compute operation mode—48M HIRC mode, 48 MHz core / 24 MHz flash, V_{DD} = 3.0 V					2
	• at 25 °C	—	5.76	6.40	mA	
	• at 105 °C	—	6.04	6.68		
I_{DD_RUNCO}	Running While(1) loop in flash in compute operation mode—48M HIRC mode, 48 MHz core / 24 MHz flash, V_{DD} = 3.0 V					
	• at 25 °C	—	3.21	3.85	mA	
	• at 105 °C	—	3.49	4.13		
I_{DD_RUN}	Run mode current—48M HIRC mode, running CoreMark in Flash all peripheral clock disable 48 MHz core/24 MHz flash, V_{DD} = 3.0 V					2
	• at 25 °C	—	6.45	7.09	mA	
	• at 105 °C	—	6.75	7.39		
I_{DD_RUN}	Run mode current—48M HIRC mode, running CoreMark in flash all peripheral clock disable, 24 MHz core/12 MHz flash, V_{DD} = 3.0 V					2
	• at 25 °C	—	3.95	4.59		
	• at 105 °C	—	4.23	4.87	mA	

Table continues on the next page...

Table 9. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• at 85 °C	—	102.92	162.20		
	• at 105 °C					
I_{DD_LLS}	Low-leakage stop mode current, all peripheral disable, at 3.0 V				μA	
	• at 25 °C and below	—	2.06	3.33		
	• at 50 °C	—	4.72	6.85		
	• at 70 °C	—	8.13	13.30		
	• at 85 °C	—	13.34	24.70		
	• at 105 °C	—	41.08	52.43		
I_{DD_LLS}	Low-leakage stop mode current with RTC current, at 3.0 V				μA	
	• at 25 °C and below	—	2.46	3.73		
	• at 50 °C	—	5.12	7.25		
	• at 70 °C	—	8.53	11.78		
	• at 85 °C	—	13.74	18.91		
	• at 105 °C	—	41.48	52.83		
I_{DD_LLS}	Low-leakage stop mode current with RTC current, at 1.8 V				μA	3
	• at 25 °C and below	—	2.35	2.70		
	• at 50 °C	—	4.91	6.75		
	• at 70 °C	—	8.32	11.78		
	• at 85 °C	—	13.44	18.21		
	• at 105 °C	—	40.47	51.85		
I_{DD_VLLS3}	Very-low-leakage stop mode 3 current, all peripheral disable, at 3.0 V				μA	
	• at 25 °C and below	—	1.45	1.85		
	• at 50 °C	—	3.37	4.39		
	• at 70 °C	—	5.76	8.48		
	• at 85 °C	—	9.72	14.30		
	• at 105 °C	—	30.41	37.50		
I_{DD_VLLS3}	Very-low-leakage stop mode 3 current with RTC current, at 3.0 V				μA	3
	• at 25 °C and below	—	2.05	2.45		
	• at 50 °C	—	3.97	4.99		
	• at 70 °C	—	6.36	9.08		
	• at 85 °C	—	10.32	14.73		
	• at 105 °C	—	31.01	38.10		

Table continues on the next page...

Table 10. Low power mode peripheral adders — typical value (continued)

Symbol	Description	Temperature (°C)						Unit
		-40	25	50	70	85	105	
								nA
I_{CMP}	CMP peripheral adder measured by placing the device in VLLS1 mode with CMP enabled using the 6-bit DAC and a single external input for compare. Includes 6-bit DAC power consumption.	22	22	22	22	22	22	µA
I_{UART}	UART peripheral adder measured by placing the device in STOP or VLPS mode with selected clock source waiting for RX data at 115200 baud rate. Includes selected clock source power consumption. • IRC8M (8 MHz internal reference clock) • IRC2M (2 MHz internal reference clock)	114 34	114 34	114 34	114 34	114 34	114 34	µA
I_{TPM}	TPM peripheral adder measured by placing the device in STOP or VLPS mode with selected clock source configured for output compare generating 100 Hz clock signal. No load is placed on the I/O generating the clock signal. Includes selected clock source and I/O switching currents. • IRC8M (8 MHz internal reference clock) • IRC2M (2 MHz internal reference clock)	147 42	147 42	147 42	147 42	147 42	147 42	µA
I_{BG}	Bandgap adder when BGEN bit is set and device is placed in VLPx or VLLSx mode.	45	45	45	45	45	45	µA
I_{ADC}	ADC peripheral adder combining the measured values at V_{DD} and V_{DDA} by placing the device in STOP or VLPS mode. ADC is configured for low power mode using the internal clock and continuous conversions.	330	330	330	330	330	330	µA
I_{LCD}	LCD peripheral adder measured by placing the device in VLLS1 mode with external 32 kHz crystal enabled by means of the OSC0_CR[EREFSTEN, EREFSTEN] bits. VIREG disabled, resistor bias network enabled, 1/8 duty cycle, 8 x 36 configuration for driving 288 Segments, 32 Hz frame rate, no LCD glass connected. Includes ERCLK32K (32 kHz external crystal) power consumption.	4.5	4.5	4.5	4.5	4.5	4.5	µA

2.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG-Lite in HIRC for run mode, and LIRC for VLPR mode
- No GPIOs toggled
- Code execution from flash
- For the ALLOFF curve, all peripheral clocks are disabled except FTFA

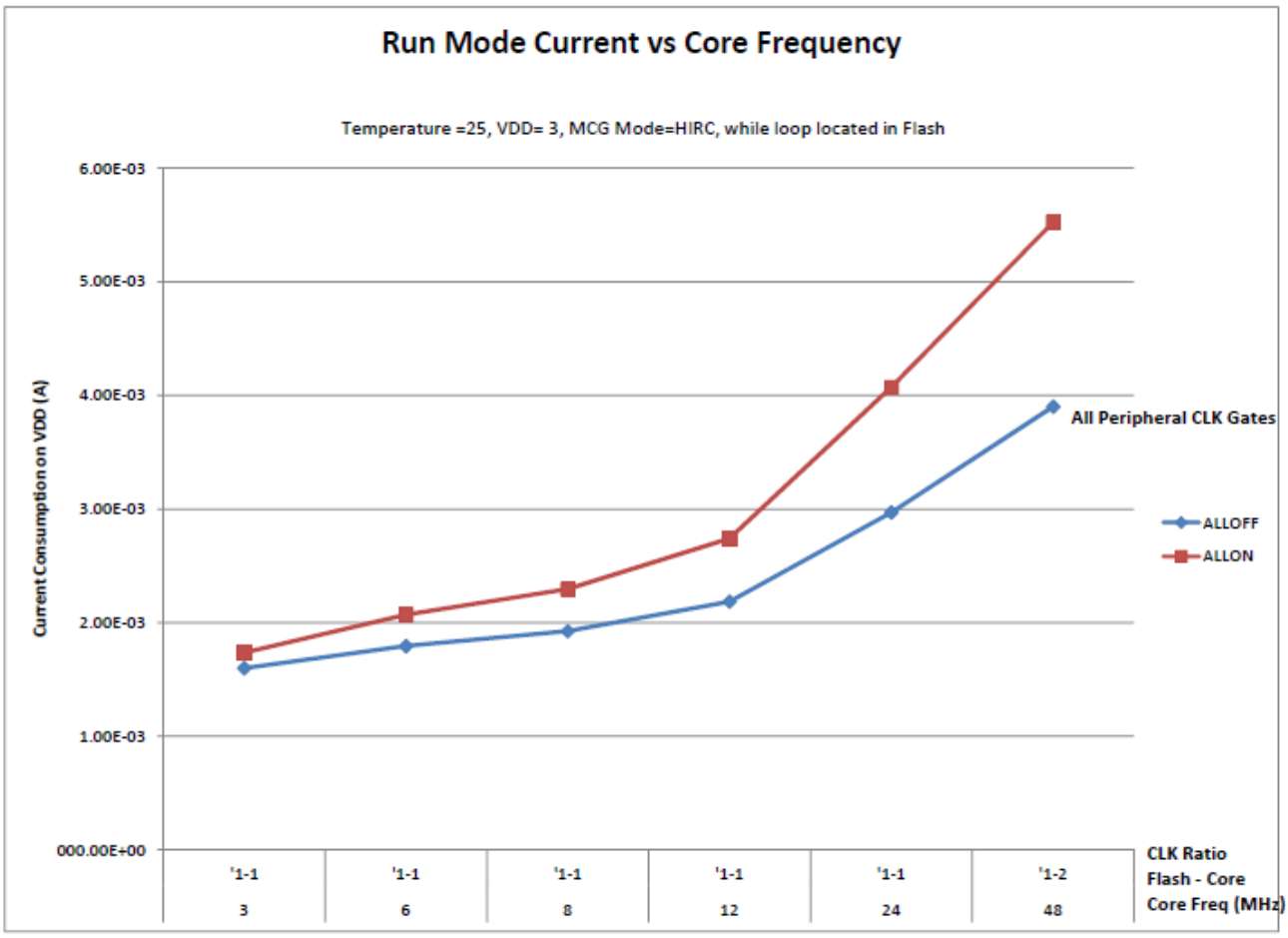


Figure 2. Run mode supply current vs. core frequency

1. Maximum T_A can be exceeded only if the user ensures that T_J does not exceed the maximum. The simplest method to determine T_J is: $T_J = T_A + R_{\theta JA} \times$ chip power dissipation.

2.4.2 Thermal attributes

Table 16. Thermal attributes

Board type	Symbol	Description	64 LQFP	64 MAPBGA	Unit	Notes
Single-layer (1S)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	70	50.3	°C/W	1
Four-layer (2s2p)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	51	42.9	°C/W	
Single-layer (1S)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	58	41.4	°C/W	
Four-layer (2s2p)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	45	38.0	°C/W	
—	$R_{\theta JB}$	Thermal resistance, junction to board	33	39.6	°C/W	2
—	$R_{\theta JC}$	Thermal resistance, junction to case	20	27.3	°C/W	3
—	Ψ_{JT}	Thermal characterization parameter, junction to package top outside center (natural convection)	4	0.4	°C/W	4
—	Ψ_{JB}	Thermal characterization parameter, junction to package bottom (natural convection)	-	12.6	°C/W	5

1. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)*, or EIA/JEDEC Standard JESD51-6, *Integrated Circuit Thermal Test Method Environmental Conditions—Forced Convection (Moving Air)*.
2. Determined according to JEDEC Standard JESD51-8, *Integrated Circuit Thermal Test Method Environmental Conditions—Junction-to-Board*.
3. Determined according to Method 1012.1 of MIL-STD 883, *Test Method Standard, Microcircuits*, with the cold plate temperature used for the case temperature. The value includes the thermal resistance of the interface material between the top of the package and the cold plate.
4. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)*.
5. Thermal characterization parameter indicating the temperature difference between package bottom center and the junction temperature per JEDEC JESD51-12. When Greek letters are not available, the thermal characterization parameter is written as Psi-JB.

3 Peripheral operating requirements and behaviors

3.1 Core modules

3.1.1 SWD electricals

Table 17. SWD full voltage range electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
J1	SWD_CLK frequency of operation • Serial wire debug	0	25	MHz
J2	SWD_CLK cycle period	1/J1	—	ns
J3	SWD_CLK clock pulse width • Serial wire debug	20	—	ns
J4	SWD_CLK rise and fall times	—	3	ns
J9	SWD_DIO input data setup time to SWD_CLK rise	10	—	ns
J10	SWD_DIO input data hold time after SWD_CLK rise	0	—	ns
J11	SWD_CLK high to SWD_DIO data valid	—	32	ns
J12	SWD_CLK high to SWD_DIO high-Z	5	—	ns

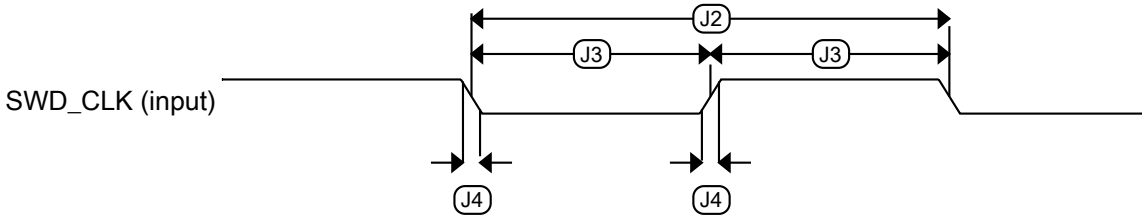


Figure 4. Serial wire clock input timing

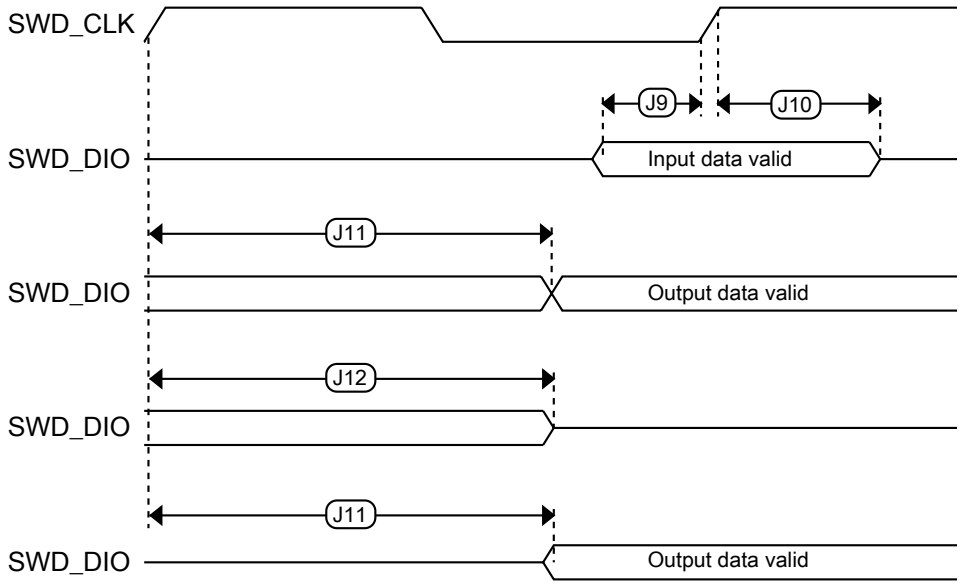


Figure 5. Serial wire data timing

3.2 System modules

There are no specifications necessary for the device's system modules.

3.3 Clock modules

3.3.1 MCG-Lite specifications

Table 18. IRC48M specification

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD}	Supply current	—	400	500	µA	—
f_{IRC}	Output frequency	—	48	—	MHz	—
$\Delta f_{irc48m\_ol\_lv}$	Open loop total deviation of IRC48M frequency at low voltage (VDD=1.71V-1.89V) over temperature	—	± 0.5	± 1.5	$\%f_{irc48m}$	1
$\Delta f_{irc48m\_ol\_hv}$	Open loop total deviation of IRC48M frequency at high voltage (VDD=1.89V-3.6V) over temperature	—	± 0.5	± 1.0	$\%f_{irc48m}$	1

Table continues on the next page...

Table 18. IRC48M specification (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
T_j	Period jitter (RMS)	—	35	150	ps	—
T_{su}	Startup time	—	2	3	µs	—

1. The maximum value represents characterized results equivalent to mean plus or minus three times the standard deviation (mean +/-3sigma).

Table 19. IRC8M/2M specification

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD_2M}	Supply current in 2 MHz mode	—	14	17	µA	—
I_{DD_8M}	Supply current in 8 MHz mode	—	30	35	µA	—
f_{IRC_2M}	Output frequency	—	2	—	MHz	—
f_{IRC_8M}	Output frequency	—	8	—	MHz	—
$f_{IRC\_T\_2M}$	Output frequency range (trimmed)	—	—	±3	$\%f_{IRC}$	—
$f_{IRC\_T\_8M}$	Output frequency range (trimmed)	—	—	±3	$\%f_{IRC}$	—
T_{su_2M}	Startup time	—	—	12.5	µs	—
T_{su_8M}	Startup time	—	—	12.5	µs	—

3. C_x,C_y can be provided by using the integrated capacitors when the low frequency oscillator (RANGE = 00) is used. For all other cases external capacitors must be used.
4. When low power mode is selected, R_F is integrated and must not be attached externally.
5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.

3.3.2.2 Oscillator frequency specifications

Table 21. Oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{osc_lo}	Oscillator crystal or resonator frequency — low-frequency mode (MCG_C2[RANGE]=00)	32	—	40	kHz	
$f_{osc\_hi\_1}$	Oscillator crystal or resonator frequency — high-frequency mode (low range) (MCG_C2[RANGE]=01)	3	—	8	MHz	
$f_{osc\_hi\_2}$	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	8	—	32	MHz	
f_{ec_extal}	Input clock frequency (external clock mode)	—	—	48	MHz	1, 2
t_{dc_extal}	Input clock duty cycle (external clock mode)	40	50	60	%	
t_{cst}	Crystal startup time — 32 kHz low-frequency, low-power mode (HGO=0)	—	750	—	ms	3, 4
	Crystal startup time — 32 kHz low-frequency, high-gain mode (HGO=1)	—	250	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), low-power mode (HGO=0)	—	0.6	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), high-gain mode (HGO=1)	—	1	—	ms	

1. Other frequency limits may apply when external clock is being used as a reference for the FLL
2. When transitioning from FEI or FBI to FBE mode, restrict the frequency of the input clock so that, when it is divided by FRDIV, it remains within the limits of the DCO input clock frequency.
3. Proper PC board layout procedures must be followed to achieve specifications.
4. Crystal startup time is defined as the time between the oscillator being enabled and the OSCINIT bit in the MCG_S register being set.

3.4 Memories and memory interfaces

3.4.1 Flash electrical specifications

This section describes the electrical characteristics of the flash memory module.

3.6.1.1 16-bit ADC operating conditions

Table 26. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	—
ΔV_{DDA}	Supply voltage	Delta to V_{DD} ($V_{DD} - V_{DDA}$)	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V_{SS} ($V_{SS} - V_{SSA}$)	-100	0	+100	mV	2
V_{REFH}	ADC reference voltage high		1.13	V_{DDA}	V_{DDA}	V	3
V_{REFL}	ADC reference voltage low		V_{SSA}	V_{SSA}	V_{SSA}	V	3
V_{ADIN}	Input voltage	• 16-bit differential mode • All other modes	VREFL VREFL	— —	31/32 × VREFH VREFH	V	—
C_{ADIN}	Input capacitance	• 16-bit mode • 8-bit / 10-bit / 12-bit modes	— —	8 4	10 5	pF	—
R_{ADIN}	Input series resistance		—	2	5	kΩ	—
R_{AS}	Analog source resistance (external)	13-bit / 12-bit modes f_{ADCK} < 4 MHz	—	—	5	kΩ	4
f_{ADCK}	ADC conversion clock frequency	≤ 13-bit mode	1.0	—	24	MHz	5
f_{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	5
C_{rate}	ADC conversion rate	≤ 13-bit modes No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	20.000	—	1200	ksps	6
C_{rate}	ADC conversion rate	16-bit mode No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	37.037	—	461.467	ksps	6

1. Typical values assume V_{DDA} = 3.0 V, Temp = 25 °C, f_{ADCK} = 1.0 MHz, unless otherwise stated. Typical values are for reference only, and are not tested in production.
2. DC potential difference.
3. VREFH can act as VREF_OUT when VREFV1 module is enabled.
4. This resistance is external to MCU. To achieve the best results, the analog source resistance must be kept as low as possible. The results in this data sheet were derived from a system that had < 8 Ω analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1 ns.
5. To use the maximum ADC conversion clock frequency, CFG2[ADHSC] must be set and CFG1[ADLPC] must be clear.
6. For guidelines and examples of conversion rate calculation, download the ADC calculator tool.

Table 30. VREF limited-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T_A	Temperature	0	50	°C	—

Table 31. VREF limited-range operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim	1.173	1.225	V	—

3.6.3 CMP and 6-bit DAC electrical specifications

Table 32. Comparator and 6-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Supply voltage	1.71	—	3.6	V
I_{DDHS}	Supply current, High-speed mode (EN=1, PMODE=1)	—	—	200	µA
I_{DDLS}	Supply current, low-speed mode (EN=1, PMODE=0)	—	—	20	µA
V_{AIN}	Analog input voltage	V_{SS} – 0.3	—	V_{DD}	V
V_{AIO}	Analog input offset voltage	—	—	20	mV
V_H	Analog comparator hysteresis[1]				
	• CR0[HYSTCTR] = 00	—	5	—	mV
	• CR0[HYSTCTR] = 01	—	10	—	mV
	• CR0[HYSTCTR] = 10	—	20	—	mV
	• CR0[HYSTCTR] = 11	—	30	—	mV
V_{CMPOh}	Output high	V_{DD} – 0.5	—	—	V
V_{CMPOl}	Output low	—	—	0.5	V
t_{DHS}	Propagation delay, high-speed mode (EN=1, PMODE=1)	20	50	200	ns
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	80	250	600	ns
	Analog comparator initialization delay[2]	—	—	40	µs
I_{DAC6b}	6-bit DAC current adder (enabled)	—	7	—	µA
INL	6-bit DAC integral non-linearity	–0.5	—	0.5	LSB[3]
DNL	6-bit DAC differential non-linearity	–0.3	—	0.3	LSB

1. Typical hysteresis is measured with input voltage range limited to 0.6 to V_{DD}–0.6 V.
2. Comparator initialization delay is defined as the time between software writes to change control inputs (Writes to CMP_DACCR[DACEN], CMP_DACCR[VRSEL], CMP_DACCR[VOSEL], CMP_MUXCR[PSEL], and CMP_MUXCR[MSEL]) and the comparator output settling to a stable level.
3. 1 LSB = $V_{reference}$/64

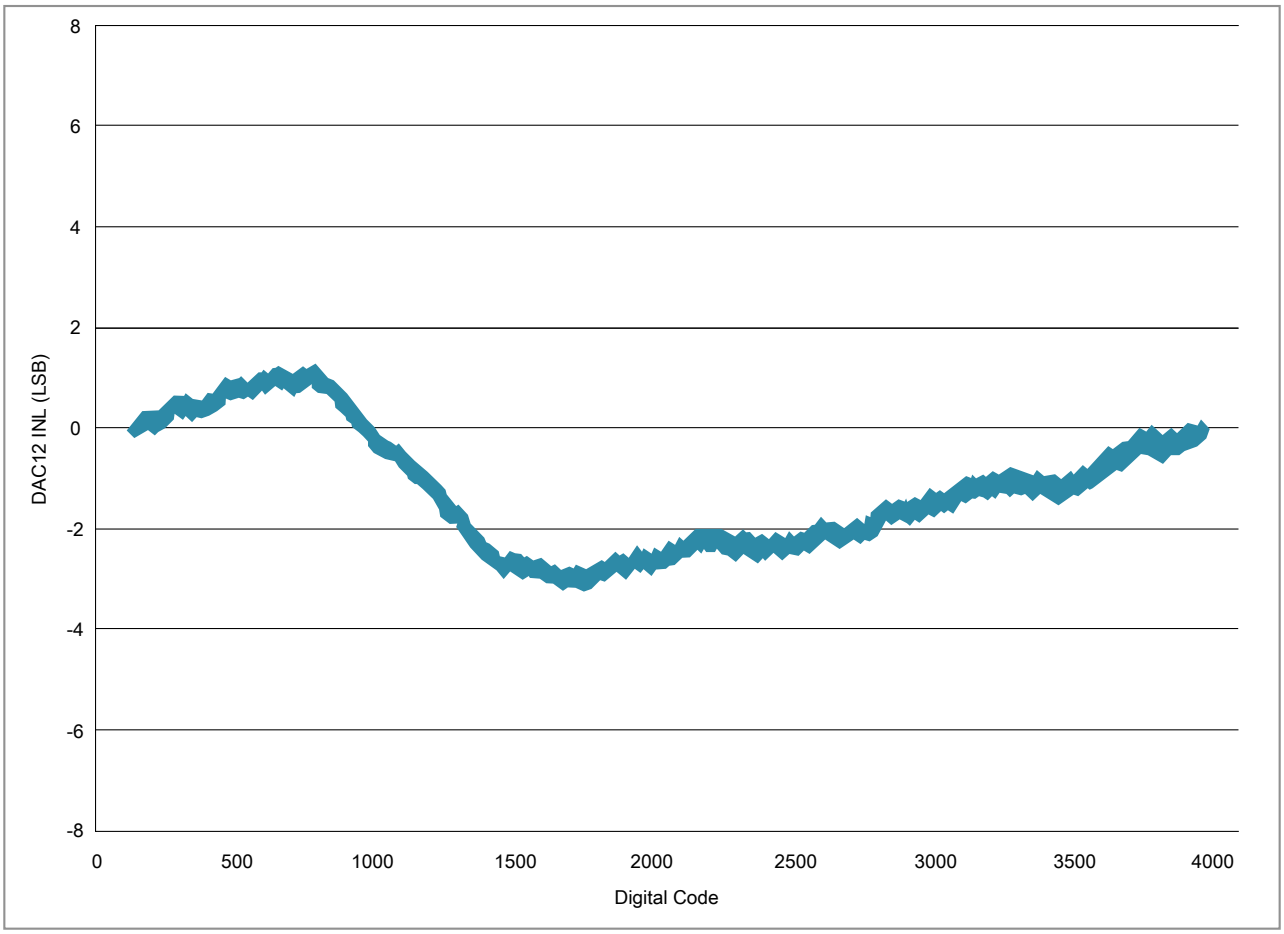


Figure 12. Typical INL error vs. digital code

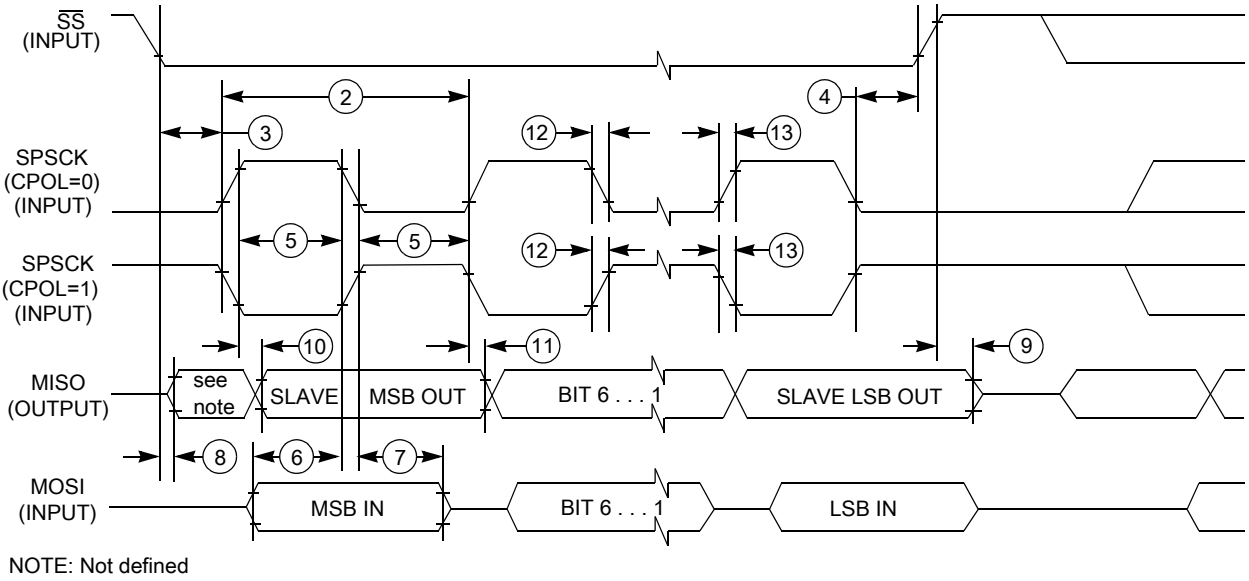


Figure 17. SPI slave mode timing (CPHA = 1)

3.8.2 I^2C

3.8.2.1 Inter-Integrated Circuit Interface (I2C) timing

Table 39. I2C timing

Characteristic	Symbol	Standard Mode		Fast Mode		Unit
		Minimum	Maximum	Minimum	Maximum	
SCL Clock Frequency	f_{SCL}	0	100	0	400[1]	kHz
Hold time (repeated) START condition. After this period, the first clock pulse is generated.	t_{HD}; STA	4	—	0.6	—	µs
LOW period of the SCL clock	t_{LOW}	4.7	—	1.25	—	µs
HIGH period of the SCL clock	t_{HIGH}	4	—	0.6	—	µs
Set-up time for a repeated START condition	t_{SU}; STA	4.7	—	0.6	—	µs
Data hold time for I^2C bus devices	t_{HD}; DAT	0[2]	3.45[3]	0[4]	0.9[2]	µs
Data set-up time	t_{SU}; DAT	250[5]	—	100[3, 6]	—	ns
Rise time of SDA and SCL signals	t_r	—	1000	20 +0.1C_b[7]	300	ns
Fall time of SDA and SCL signals	t_f	—	300	20 +0.1C_b[6]	300	ns
Set-up time for STOP condition	t_{SU}; STO	4	—	0.6	—	µs
Bus free time between STOP and START condition	t_{BUF}	4.7	—	1.3	—	µs
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	N/A	N/A	0	50	ns

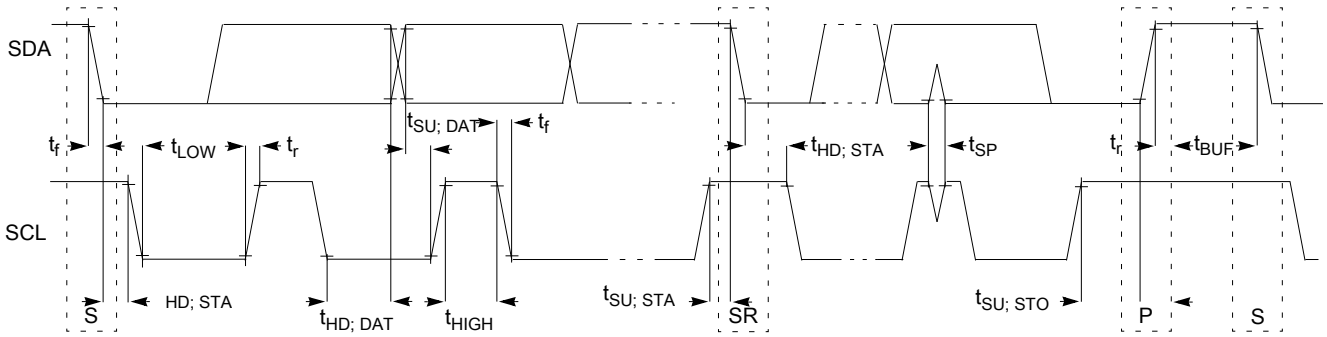


Figure 18. Timing definition for devices on the I²C bus

3.8.3 UART

See General switching specifications.

3.8.4 I2S/SAI switching specifications

This section provides the AC timing for the I2S/SAI module in master mode (clocks are driven) and slave mode (clocks are input). All timing is given for noninverted serial clock polarity (TCR2[BCP] is 0, RCR2[BCP] is 0) and a noninverted frame sync (TCR4[FSP] is 0, RCR4[FSP] is 0). If the polarity of the clock and/or the frame sync have been inverted, all the timing remains valid by inverting the bit clock signal (BCLK) and/or the frame sync (FS) signal shown in the following figures.

3.8.4.1 Normal Run, Wait and Stop mode performance over the full operating voltage range

This section provides the operating performance over the full operating voltage for the device in Normal Run, Wait and Stop modes.

Table 41. I2S/SAI master mode timing

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	40	—	ns
S2	I2S_MCLK (as an input) pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	15.5	ns

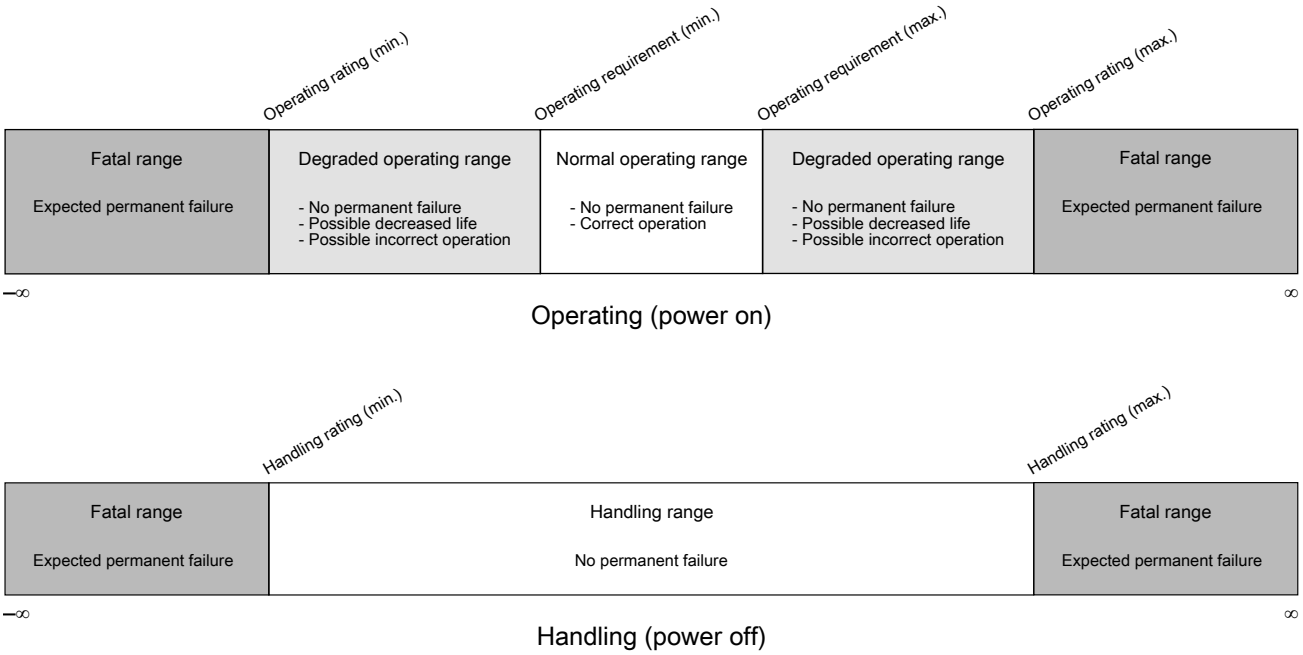
Table continues on the next page...

Table 45. LCD electricals (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• RVTRIM=1110	—	1.01	—		
	• RVTRIM=0001	—	1.02	—		
	• RVTRIM=1001	—	1.03	—		
	• RVTRIM=0101	—	1.05	—		
	• RVTRIM=1101	—	1.06	—		
	• RVTRIM=0011	—	1.07	—		
	• RVTRIM=1011	—	1.08	—		
	• RVTRIM=0111	—	1.09	—		
	• RVTRIM=1111					
Δ_{RTRIM}	V_{IREG} TRIM resolution	—	—	3.0	% V_{IREG}	
I_{VIREG}	V_{IREG} current adder — RVEN = 1	—	1	—	µA	
I_{RBIAS}	RBIAS current adder					
	• LADJ = 10 or 11 — High load (LCD glass capacitance ≤ 8000 pF)	—	10	—	µA	
	• LADJ = 00 or 01 — Low load (LCD glass capacitance ≤ 2000 pF)	—	1	—	µA	
R_{RBIAS}	RBIAS resistor values					
	• LADJ = 10 or 11 — High load (LCD glass capacitance ≤ 8000 pF)	—	0.28	—	MΩ	
	• LADJ = 00 or 01 — Low load (LCD glass capacitance ≤ 2000 pF)	—	2.98	—	MΩ	
VLL1	VLL1 voltage	—	—	V_{IREG}	V	4
VLL2	VLL2 voltage	—	—	2 x V_{IREG}	V	4
VLL3	VLL3 voltage	—	—	3 x V_{IREG}	V	4
VLL1	VLL1 voltage	—	—	V_{DDA} / 3	V	5
VLL2	VLL2 voltage	—	—	V_{DDA} / 1.5	V	5
VLL3	VLL3 voltage	—	—	V_{DDA}	V	5

1. The actual value used could vary with tolerance.
2. For highest glass capacitance values, LCD_GCR[LADJ] should be configured as specified in the LCD Controller chapter within the device's reference manual.
3. V_{IREG} maximum should never be externally driven to any level other than V_{DD} - 0.15 V
4. VLL1, VLL2 and VLL3 are a function of V_{IREG} only when the regulator is enabled (GCR[RVEN]=1) and the charge pump is enabled (GCR[CPSEL]=1).
5. VLL1, VLL2 and VLL3 are a function of V_{DDA} only under either of the following conditions:
   - The charge pump is enabled (GCR[CPSEL]=1), the regulator is disabled (GCR[RVEN]=0), and VLL3 = V_{DDA} through the internal power switch (GCR[VSUPPLY]=0).
   - The resistor bias string is enabled (GCR[CPSEL]=0), the regulator is disabled (GCR[RVEN]=0), and VLL3 is connected to V_{DDA} externally (GCR[VSUPPLY]=1).

8.4 Relationship between ratings and operating requirements



8.5 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

9 Revision History

The following table provides a revision history for this document.

Table 47. Revision History

Rev. No.	Date	Substantial Changes
3	09 August 2014	Initial Public release • Updated Table 9 - Power consumption operating behaviors.
4	03 March 2015	• Updated the features and completed the ordering information. • Removed thickness dimension from package diagrams.

Table continues on the next page...

Table 47. Revision History (continued)

Rev. No.	Date	Substantial Changes

		• Updated Related Resources table to include Chip Errata resource name and Package Drawing part numbers in the respective rows.
		• Updated Table 7. Voltage and current operating behaviors.
		  • Specified correct max. value for I_{IN}.
		• Updated Table - 9 Power consumption operating behaviors.
		  • Rows added for IDD for reset pin hold low ($I_{DD\_RESET\_LOW}$) at 1.7V and 3V.
		  • Measurement unit updated for I_{DD_VLLS1} from nA to µA.
		  • Footnote 1 was moved in the beginning of the table as text.
		• Added Table - 11 EMC radiated emissions operating behaviors for 64-pin LQFP package under section 2.2.6.
		• Updated Table - 18 (IRC48M specification) and Table - 19 (IRC8M/2M specification) under section 3.3.1 - 'MCG-Lite specifications'.
		  • Removed supply voltage (V_{DD}), temperature range (T), untrimmed (f_{IRC_UT}), trim function (Δf_{IRC_C}, Δf_{IRC_F}) data from Table - 18 (IRC48M specification).
		  • Removed supply voltage (V_{DD}), temperature range (T) data from Table - 19 (IRC8M/2M specification).
		• Added Figure 6. IRC8M Frequency Drift vs Temperature curve after Table - 19 (IRC8M/2M specification).
		• Updated Table 29. VREF full-range operating behaviors.
		  • Removed A_c(Aging coefficient) row.
		  • Added $T_{chop\_osc\_stup}$ parameter.
		  • Updated typical value of the V_{out} parameter.
		• Added tables: "I2C timing" and "I2C 1Mbit/s timing" under section - I^2C.
		• Added VREF specifications (V_{REFH} and V_{REFL}) to Table 26. 16-bit ADC operating conditions.
		• Removed note: “This device does not have the USB_CLKIN signal available.”

5	12 August 2015	• In Table 9. Power consumption operating behaviors:
		  • Updated Max. values of I_{DD_WAIT}, I_{DD_VLPW}, I_{DD_STOP}, I_{DD_VLPS}, I_{DD_LLS}, I_{DD_VLLS3}, I_{DD_VLLS1}, I_{DD_VLLS0}.
		  • Modified unit of I_{DD_VLLS0} from nA to µA.
		  • Removed $I_{DD\_RESET\_LOW}$ information.
		• In Table 13. Device clock specifications, added a footnote for normal run mode.
		• In Table 15. Thermal operating requirements, modified the footnote for Ambient temperature.
		• In Table 18. IRC48M specification, removed f_{IRC_T} data and added $\Delta f_{irc48m\_of\_lv}$ and $\Delta f_{irc48m\_of\_hv}$ specifications.
		• In Table 26. 16-bit ADC operating conditions, updated Max. value of f_{ADCK} and C_{rate}.

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